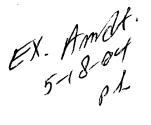
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AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions, and listing, of claims in the application:

Claim 1 (Currently amended): An RF plasma generator comprising:

- a) a variable frequency RF generator, comprising an H-bridge and an RF output, that generates electromagnetic radiation having a power;
- b) a matching network comprising at least one variable impedance component, the matching network including a first port that is electromagnetically coupled to the output of the RF generator and a second port, the variable impedance component providing an electrically controllable variable capacitance;
- a load that is electromagnetically coupled to the second port of the matching network; and
- d) a plasma chamber for containing a plasma having a power, the plasma chamber being electromagnetically coupled to the load, the plasma chamber receiving electromagnetic radiation having a power from the load, wherein

adjusting at least one of the frequency of the RF generator and the variable impedance component in the matching network changes the power in the plasma.

Claim 2 (Original): The RF plasma generator of claim 1 wherein the load is reactive.

Claim 3 (Original): The RF plasma generator of claim 1 wherein the matching network transforms the impedance of the reactive load to a substantially real impedance.

Claim 4 (Original): The RF plasma generator of claim 1 wherein the load comprises an inductive load.

Claim 5 (Original): The RF plasma generator of claim 1 wherein the load comprises a capacitive load.

Claim 6 (Original): The RF plasma generator of claim 1 wherein the adjusting the at least one of the frequency of the RF generator and the variable impedance component in the matching

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network substantially matches an impedance of the load to an output impedance of the RF generator.

Claim 7 (Original): The RF plasma generator of claim 1 wherein the adjusting the at least one of the frequency of the RF generator and the variable impedance component in the matching network increases the power in the plasma.

Claim 8 (Original): The RF plasma generator of claim 1 wherein the matching network has a substantially resistive impedance at a frequency of the electromagnetic radiation.

Claim 9 (Original): The RF plasma generator of claim 1 wherein the matching network comprises a series combination of an amplifier and a variable capacitance capacitor.

Claim 10 (Cancelled)

Claim 11 (Original): The RF plasma generator of claim 1 wherein the RF generator and the matching network are physically integrated in a device housing.

Claim 12 (Original): The RF plasma generator of claim 1 further comprising a sensor that measurers power delivered to the load.

Claim 13 (Original): The RF plasma generator of claim 1 wherein the at least one of the frequency of the RF generator and the variable impedance component in the matching network is adjusted in response to a measurement of the sensor.

Claim 14 (Original): The RF plasma generator of claim 13 wherein the at least one of the frequency of the RF generator and the variable impedance component in the matching network is adjusted to minimize power reflected from the plasma.

Claim 15 (Original): The RF plasma generator of claim 13 wherein the at least one of the frequency of the RF generator and the variable impedance component in the matching network is adjusted to maximize power reflected from the plasma.

Claim 16 (Original): The RF plasma generator of claim 1 wherein the plasma has a power that is related to the power of the electromagnetic radiation that is coupled from the load to the plasma.

Claim 17 (Original): The RF plasma generator of claim 1 wherein the matching network comprises switching transistors.

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Claim 18 (Withdrawn): A method for stabilizing a plasma, the method comprising:

- a) generating electromagnetic radiation with an RF generator that includes an H-bridge, the electromagnetic radiation having a power that is related to a DC voltage applied to an RF generator bus;
- b) coupling the electromagnetic radiation to a plasma;
- c) sensing the power in the electromagnetic radiation generated by the RF generator; and

adjusting the DC voltage applied to the RF generator bus in response to the sensed power so as to maintain a substantially constant power in the plasma.

Claim 19 (Withdrawn): The method of claim 18 wherein the sensing the power in the plasma comprises measuring a voltage and a current of the electromagnetic radiation.

Claim 20 (Withdrawn): The method of claim 18 wherein the power is maintained substantially constant with a time constant of less than 10kHz.

Claim 21 (Withdrawn): A method for stabilizing a plasma, the method comprising:

- a) generating electromagnetic radiation with an RF generator that includes an H-bridge, the electromagnetic radiation having a power that is related to a DC voltage applied to an RF generator bus;
- b) coupling the electromagnetic radiation to a plasma;
- c) measuring an impedance of the load impedance; and

adjusting the DC voltage applied to the RF generator bus in response to the measured

load impedance so as to maintain a substantially constant power in the plasma.

Claim 22 (Withdrawn): The method of claim 21 wherein the sensing the change in the load impedance comprises determining the rate of change of the power of the electromagnetic radiation with time.

Claim 23 (Withdrawn): A method for stabilizing a plasma, the method comprising:

- a) generating electromagnetic radiation with an RF generator that includes an H-bridge, the electromagnetic radiation having a power that is related to a DC voltage applied to an RF generator bus;
- b) coupling the electromagnetic radiation to a plasma;
- c) sensing a power of the plasma; and

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adjusting the DC voltage applied to the RF generator bus in response to the sensed power of the plasma so as to maintain a substantially constant power in the plasma.

Claim 24 (Withdrawn): The method of claim 23 wherein the sensing the power of the plasma comprises measuring optical radiation emitted by the plasma.

Claim 25 (Withdrawn): A method for stabilizing a plasma, the method comprising:

- a) generating electromagnetic radiation with an RF generator that includes an H-bridge, the electromagnetic radiation having a power that is related to a DC voltage applied to an RF generator bus;
- b) electromagnetically coupling the electromagnetic radiation to an impedance matching network;
- c) sensing a power of the electromagnetic radiation propagating through the matching impedance;
- d) coupling the electromagnetic radiation to a plasma; and
- e) adjusting the DC voltage applied to the RF generator bus in response to the sensed power of the electromagnetic radiation propagating through the matching impedance so as to maintain a substantially constant power in the plasma.

Claim 26 (Withdrawn): A method for stabilizing a plasma, the method comprising:

- a) generating electromagnetic radiation with an RF generator;
- b) coupling the electromagnetic radiation to a plasma;
- c) sensing a power related to the power in the plasma; and
- adjusting an output impedance of the RF generator in response to the sensed power related to the power in the plasma to an impedance that maintains at least one plasma parameter at a substantially constant value.

Claim 27 (Withdrawn): The method of claim 26 wherein the power related to the power in the plasma comprises a power generated by the RF generator.

Claim 28 (Withdrawn): The method of claim 26 wherein the impedance that maintains a substantially constant power in the plasma comprises a predetermined impedance.

Claim 29 (Withdrawn): The method of claim 26 wherein the power is maintained substantially constant with a time constant of less than 10kHz.

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Claim 30 (Cancelled)

Claim 31 (Cancelled)

Claim 32 (Currently amended): An RF plasma generator comprising:

- a) an RF generator including an RF output that generates electromagnetic radiation at a frequency;
- b) a matching network comprising a 3-port solid state device that <u>electrically</u> controls a change of a capacitance of a component in the matching network, an impedance of the matching network being substantially resistive at the frequency of the RF electromagnetic radiation, the matching network including a first port that is electromagnetically coupled to the output of the RF generator and a second port[[,]];
- a load that is electromagnetically coupled to the second port of the matching network; and
- d) a plasma chamber for containing a plasma therein, the plasma chamber being electromagnetically coupled to the load.

Claim 33 (Currently amended): An RF plasma generator comprising:

- a) an RF generator, comprising an H-bridge and an RF output, that generates electromagnetic radiation having a power;
- a matching network comprising a series combination of an amplifier and an electrically controllable variable capacitance capacitor, the matching network including a first port that is electromagnetically coupled to the output of the RF generator and a second port;
- c) a load that is electromagnetically coupled to the second port of the matching network; and
- d) a plasma chamber for containing a plasma having a power, the plasma chamber being electromagnetically coupled to the load, the plasma chamber receiving electromagnetic radiation having a power from the load, wherein

adjusting at least one of the frequency of the RF generator and the variable impedance component in the matching network changes the power in the plasma.

Claim 34 (Cancelled)

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Claim 35 (Currently amended): An RF plasma generator comprising:

- a) a variable frequency RF generator including an RF output that generates an RF signal having a power;
- a matching network comprising at least one variable impedance component and a 3-port solid state device that <u>electrically</u> controls a change of a capacitance of a component in the matching network, the matching network including a first port that receives the RF signal and a second port;
- c) a load that is electrically coupled to the second port of the matching network; and
- d) a plasma chamber for containing a plasma having a power, the plasma chamber being electromagnetically coupled to the load via the RF signal, wherein adjusting at least one of the frequency of the RF generator and the variable impedance component in the matching network changes the power in the plasma.